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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/717,403	11/19/2003	Patrick Y. Huet	58551.US	8656
60838 I NG/KI A IOI	7590 12/27/2007 INT CUSTOMER	EXAMINER		
C/O LUEDEK	A, NEELY & GRAHAM, F	VALENTIN	VALENTIN, JUAN D	
P.O. BOX 187 KNOXVILLE,		ART UNIT	PAPER NUMBER	
			2877 ·	
•	•			
			NOTIFICATION DATE	DELIVERY MODE
			12/27/2007	ELECTRONIC

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

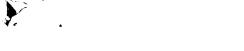
Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

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Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)		
10/717,403	HUET ET AL.		
Examiner	Art Unit		
Juan D. Valentin II	2877		

Before the Filing of an Appeal Brief	Examiner	Art Unit	
	Juan D. Valentin II	2877	
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence add	ress
THE REPLY FILED 12 December 2007 FAILS TO PLACE THIS 1. ☑ The reply was filed after a final rejection, but prior to or on this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a No a Request for Continued Examination (RCE) in compliance	the same day as filing a Notice of wing replies: (1) an amendment, aff tice of Appeal (with appeal fee) in c	Appeal. To avoid aba idavit, or other eviden compliance with 37 CI	ice, which FR 41.31; or (3)
time periods: a) The period for reply expiresmonths from the mailing b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire is Examiner Note: If box 1 is checked, check either box (a) or a	Advisory Action, or (2) the date set forth ater than SIX MONTHS from the mailing	g date of the final rejection	on.
TWO MONTHS OF THE FINAL REJECTION. See MPEP 7 Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of ex under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	06.07(f). on which the petition under 37 CFR 1.1 tension and the corresponding amount shortened statutory period for reply origi r than three months after the mailing da	36(a) and the appropriation of the fee. The appropring appropringly set in the final Officential Offic	te extension fee ate extension fee ce action; or (2) as
2: The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exte a Notice of Appeal has been filed, any reply must be filed AMENDMENTS	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	ns of the date of e appeal. Since
 The proposed amendment(s) filed after a final rejection, (a) They raise new issues that would require further co (b) They raise the issue of new matter (see NOTE belo (c) They are not deemed to place the application in bel appeal; and/or (d) They present additional claims without canceling a 	nsideration and/or search (see NO ow); tter form for appeal by materially re- corresponding number of finally rej	TE below); ducing or simplifying t	
NOTE: (See 37 CFR 1.116 and 41.33(a)). 4. The amendments are not in compliance with 37 CFR 1.1. 5. Applicant's reply has overcome the following rejection(s). 6. Newly proposed or amended claim(s) would be all non-allowable claim(s).	21. See attached Notice of Non-Co		•
7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is protected. The status of the claim(s) is (or will be) as follows: Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: Claim(s) withdrawn from consideration: AFFIDAVIT OR OTHER EVIDENCE		l be entered and an e	xplanation of
 The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). 	d sufficient reasons why the affidav	it or other evidence is	necessary and
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to of showing a good and sufficient reasons why it is necessary	overcome all rejections under appea	al and/or appellant fai	ls to provide a
 10. ☐ The affidavit or other evidence is entered. An explanatio REQUEST FOR RECONSIDERATION/OTHER 11. ☒ The request for reconsideration has been considered but 		-	
See attached sheet 12. Note the attached Information Disclosure Statement(s). 13. Other:	(PTO/SB/08) Paper No(s)		
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Application/Control Number: 10/717,403

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Advisory Action Continued

Response to Arguments

- 1. Applicant's arguments filed 12/12/2007 have been fully considered but they are not persuasive. It appears applicant has misunderstood the view point expressed by examiner in the Final Rejection dated Nara et al. as shown previously, while not explicitly, but rather implicitly shows that prior art methods carry out applicant's method as claimed. In Nara et al. a wafer blank is used before any circuit patterns have been transferred onto it, consisting essentially of a blank canvas. Before the plurality of circuit patterns are transferred onto the wafer, it is obviously or as applicant has claimed it, logically divided into zones which are then used to transfer circuit patterns into each zone. Taking the cited passage from Nara et al. used in section one of the Final Rejection dated 10/19/2007 as included below:
 - "A semiconductor device is formed by repeating a step of transferring a circuit pattern formed on a photomask to a semiconductor wafer by a lithographing process and an etching process. A state of the process, the presence or absence of generation of a foreign matter (particles), and the like in the manufacturing step of the semiconductor device largely exercise an influence on a manufacturing yield of the semiconductor device. To detect them early or preparatorily, a method of inspecting the circuit pattern of the semiconductor wafer in the manufacturing step of the semiconductor device has conventionally been used." (emphasis added)

Nara et al. discloses inspecting each individual circuit pattern as it is transferred onto the semiconductor wafer, which satisfies the claim limitations as claimed. It appears applicant is giving very narrow weight to the claims as scripted. Nothing in applicant's claimed method precludes the individual detection and analyzing of a wafer on a die by die basis as prior art clearly discloses and clearly shown above in the cited passage from Nara et al.

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Conclusion

The Final Rejection dated 10/19/2007 is maintained. 2.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Juan D. Valentin II whose telephone number is (571) 272-2433. The examiner can normally be reached on Mon.-Fri..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley, Jr. can be reached on (571) 272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/JDVII/ Juan D Valentin II Examiner 2877 JDV December 18, 2007